Se	arch	Note	S

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/657,199	CHEN ET AL.	
Examiner	Art Unit	<del></del>
Susan Hanley	1651	

SEARCHED			
Class	Subclass	Date	Examiner
435	43,47, 254.11, 254.1, 254.5	6/9/2006	SMH
435	254.3	6/9/2006	SMH
435	43,47	3/15/2007	SMH
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
435	43,47	3/15/2007	SMH

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
STN: REGISTRY, CAPLUS, see notes for search straegy	6/8/2006	SMH
WEST: USPAT, EPAB, JPAB, DWPI, PGPUBS, see notes for search strategy	6/9/2006	SMH
Inventor Search	6/9/2006	SMH
Interference Search	3/15/2007	SMH
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